ESD Protection Diodes

Micro-Packaged Diodes for ESD Protection

The ESD7381 is designed to protect voltage sensitive components that require ultra-low capacitance from ESD and transient voltage events. Excellent clamping capability, low capacitance, low leakage, and fast response time, make these parts ideal for ESD protection on designs where board space is at a premium. Because of its low capacitance, it is suited for use in high frequency designs such as USB 2.0 high speed and antenna line applications.

Features

- Ultra-Low Capacitance: 0.37 pF
- Low Clamping Voltage
- Small Body Outline Dimensions: 0.60 mm x 0.30 mm
- Low Body Height: 0.3 mm
- Stand–off Voltage: 3.3 V
- Low Leakage
- Insertion Loss: 0.030 dBm
- Response Time is < 1 ns
- Low Dynamic Resistance < 1 Ω
- IEC61000-4-2 Level 4 ESD Protection
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Typical Applications

- RF Signal ESD Protection
- RF Switching, PA, and Antenna ESD Protection
- Near Field Communications

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
IEC 61000–4–2 (ESD) Contact Air		±20 ±20	kV
Total Power Dissipation on FR–5 Board (Note 1) @ $T_A = 25^{\circ}C$ Thermal Resistance, Junction–to–Ambient	Ρ _D R _{θJA}	250 400	mW °C/W
Junction and Storage Temperature Range	T _J , T _{stg}	-40 to +125	°C
Lead Solder Temperature – Maximum (10 Second Duration)	ΤL	260	°C

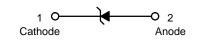
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. FR-5 = $1.0 \times 0.75 \times 0.62$ in.

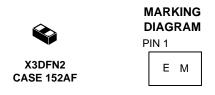
See Application Note AND8308/D for further description of survivability specs.



ON Semiconductor®

www.onsemi.com





E = Specific Device Code

M = Date Code

ORDERING INFORMATION

Device	Package	Shipping [†]
ESD7381MUT5G	X3DFN2 (Pb–Free)	15000 / Tape & Reel

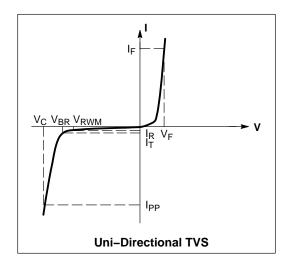
[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS

 $(T_A = 25^{\circ}C \text{ unless otherwise noted})$

· ··	,
Symbol	Parameter
I _{PP}	Maximum Reverse Peak Pulse Current
V _C	Clamping Voltage @ IPP
V _{RWM}	Working Peak Reverse Voltage
I _R	Maximum Reverse Leakage Current @ V _{RWM}
V _{BR}	Breakdown Voltage @ I _T
Ι _Τ	Test Current

*See Application Note AND8308/D for detailed explanations of datasheet parameters.

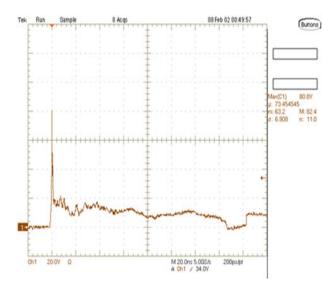


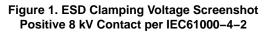
ELECTRICAL CHARACTERISTICS ($T_A = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Reverse Working Voltage	V _{RWM}				3.3	V
Breakdown Voltage (Note 2)	V _{BR}	I _T = 1 mA	5.0			V
Reverse Leakage Current	I _R	V _{RWM} = 3.3 V		< 1.0	50	nA
Clamping Voltage (Note 3)	V _C	I _{PP} = 1 A			8.0	V
Clamping Voltage (Note 3)	V _C	I _{PP} = 3 A			10	V
ESD Clamping Voltage	V _C	Per IEC61000-4-2	See	See Figures 1 and 2		
Junction Capacitance	CJ	$V_R = 0 V, f = 1 Mhz$ $V_R = 0 V, f < 1 GHz$		0.37 0.25	0.55 0.55	pF
Dynamic Resistance	R _{DYN}	TLP Pulse		0.32		Ω
Insertion Loss		f = 1 Mhz f = 8.5 GHz		0.030 0.573		dB

2. Breakdown voltage is tested from pin 1 to 2 and pin 2 to 1.

3. Non–repetitive current pulse at $T_A = 25^{\circ}C$, per IEC61000–4–5 waveform.





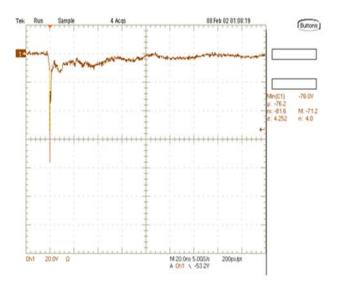
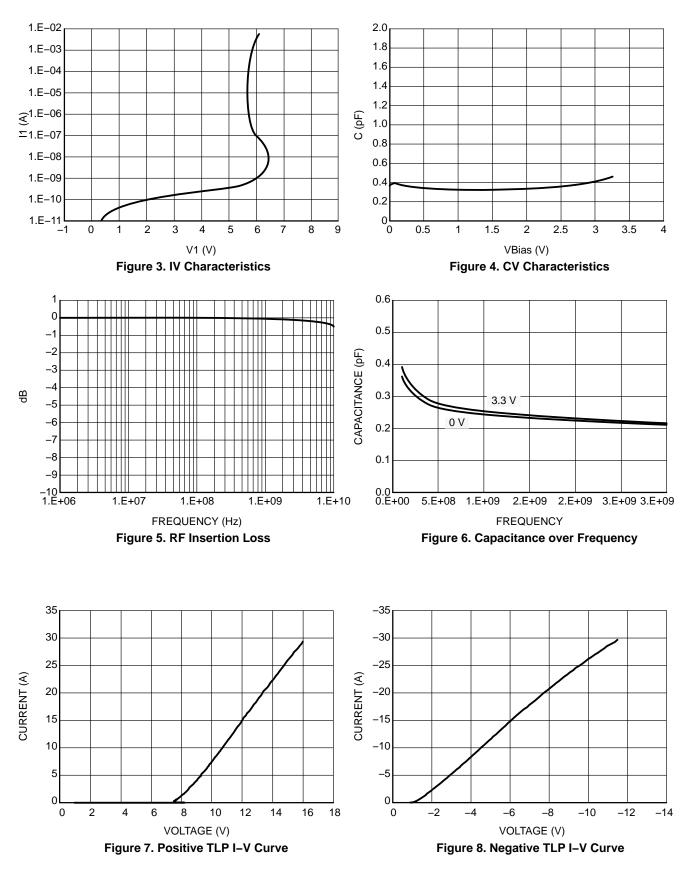


Figure 2. ESD Clamping Voltage Screenshot Negative 8 kV Contact per IEC61000-4-2



IEC 61000-4-2 Spec.

Level	Test Volt- age (kV)	First Peak Current (A)	Current at 30 ns (A)	Current at 60 ns (A)
1	2	7.5	4	2
2	4	15	8	4
3	6	22.5	12	6
4	8	30	16	8

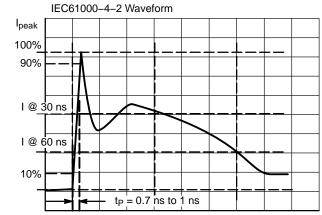


Figure 9. IEC61000-4-2 Spec

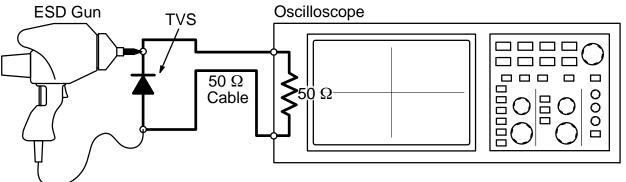
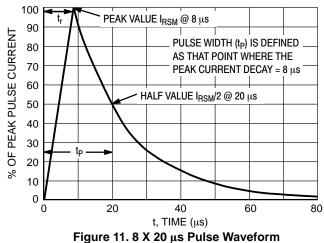


Figure 10. Diagram of ESD Test Setup

ESD Voltage Clamping

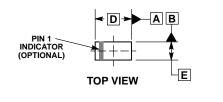
For sensitive circuit elements it is important to limit the voltage that an IC will be exposed to during an ESD event to as low a voltage as possible. The ESD clamping voltage is the voltage drop across the ESD protection diode during an ESD event per the IEC61000–4–2 waveform. Since the IEC61000–4–2 was written as a pass/fail spec for larger systems such as cell phones or laptop computers it is not clearly defined in the spec how to specify a clamping voltage

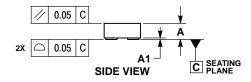
at the device level. ON Semiconductor has developed a way to examine the entire voltage waveform across the ESD protection diode over the time domain of an ESD pulse in the form of an oscilloscope screenshot, which can be found on the datasheets for all ESD protection diodes. For more information on how ON Semiconductor creates these screenshots and how to interpret them please refer to AND8307/D.

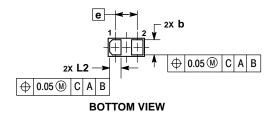


PACKAGE DIMENSIONS

X3DFN2, 0.62x0.32, 0.355P, (0201) CASE 152AF ISSUE A



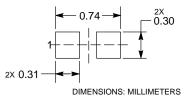








RECOMMENDED MOUNTING FOOTPRINT*



See Application Note AND8398/D for more mounting details

*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ON Semiconductor and **W** are registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of SCILLC's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typical" must be validated for each customer application by customer's technical experts. SCILLC products are not designed, intended, or authorized for use as components insystems intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized seguinates, and easonable attorney fees arising out of, directly or indirectly, any claim of personal injury or teath associated with such unintended or unauthorized copyright has and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, cos

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA Phone: 303–675–2175 or 800–344–3860 Toll Free USA/Canada Fax: 303–675–2176 or 800–344–3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800–282–9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support:

Phone: 421 33 790 2910 Japan Customer Focus Center Phone: 81–3–5817–1050 ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative

ESD7381/D